

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of Applicants: Date: January 14, 2009
Beaman et al. Group Art Unit: 2829
Serial No.: 09/382,834 Examiner: V. P. Nguyen
Filed: August 25, 1999 Docket No.: YOR919930028US5
For: **HIGH DENSITY INTEGRATED CIRCUIT APPARATUS, TEST PROBE AND METHODS OF USE THEREOF**

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

RESPONSE TO NOTICE OF FILE CORRECTED APPLICATION PAPERS

NOTICE OF ALLOWANCE MAILED DATED 12-11-2008

REMARKS

Enclosed herewith is the corrected sheet of drawings containing Figs. 21 and 22. In the original drawings this sheet had both figures labeled as Fig. 21. On the attached corrected sheet the top Figure is Fig. 21 and the bottom figure is Fig. 22.